

October 2013

FQB33N10L

N-Channel QFET® MOSFET

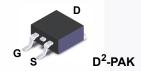
100 V, 33 A, 52 m Ω

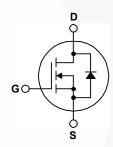
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 33 A, 100 V, $R_{DS(on)}$ = 52 m Ω (Max) @V_{GS} = 10 V, I_D = 16.5 A
- · Low Gate Charge (Typ. 30 nC)
- · Low Crss (Typ. 70 pF)
- 100% Avalanche Tested
- · 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB33N10LTM	Unit
V _{DSS}	Drain-Source Voltage		100	V
I _D	Drain Current - Continuous (T _C = 25°C)	33	А
	- Continuous (T _C = 100°	C)	23	А
I _{DM}	Drain Current - Pulsed	(Note 1)	132	А
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	430	mJ
I _{AR}	Avalanche Current	(Note 1)	33	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	12.7	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns
P_{D}	Power Dissipation (T _A = 25°C) * Power Dissipation (T _C = 25°C) - Derate above 25°C		3.75	W
			127	W
			0.85	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQB33N10LTM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	1.18	
В	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	62.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (* 1 in² pad of 2 oz copper), Max.	40	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB33N10L	FQB33N10LTM	D2-PAK	330mm	24mm	800

Electrical Characteristics

T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Uni
Off Cha	aracteristics		•	•	,	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	100			V
ΔBV_{DSS} / ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.09		V/°
I _{DSS}	Zana Oata Vallana Basis Oussat	V _{DS} = 100 V, V _{GS} = 0 V			1	μA
	Zero Gate Voltage Drain Current	V _{DS} = 80 V, T _C = 150°C			10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	n/
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	n/
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 16.5 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 16.5 \text{ A}$		0.039 0.043	0.052 0.055	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 30 V, I _D = 16.5 A		27		S
Dynam	ic Characteristics Input Capacitance	I		1250	1630	pF
C _{oss}	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		305	400	ıq Iq
C _{rss}	Reverse Transfer Capacitance			70	90	ıq Iq
	ing Characteristics					۳۰
t _{d(on)}	Turn-On Delay Time	V _{DD} = 50 V, I _D = 33 A,		17	45	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		470	950	ns
$t_{d(off)}$	Turn-Off Delay Time	Ŭ		70	150	ns
t _f	Turn-Off Fall Time	(Note 4)	/	120	250	ns
Qg	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 33 \text{ A},$		30	40	nC
	Gate-Source Charge	V _{GS} = 5 V	"	4.7		nC
Q _{gs}	Ü			16		n(

IS	Maximum Continuous Drain-Source Diode Forward Current		 	33	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		 	132	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 33 A	 	1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 33 \text{ A,}$	 90		ns
Q _{rr}	Reverse Recovery Charge	dl _F / dt = 100 A/μs	 0.26		μС

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.59mH, I_{AS} = 33A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 33A, di/dt \leq 300A/ μ s, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Essentially independent of operating temperature

Typical Characteristics

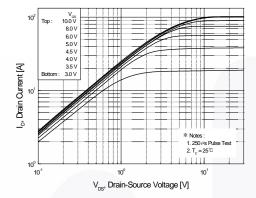


Figure 1. On-Region Characteristics

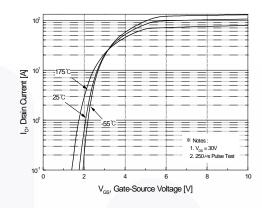


Figure 2. Transfer Characteristics

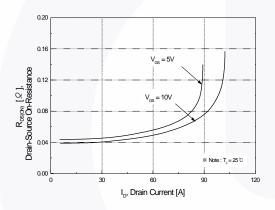


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

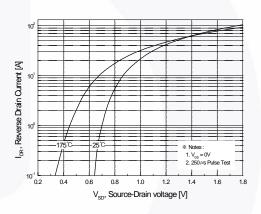


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

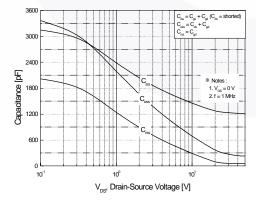


Figure 5. Capacitance Characteristics

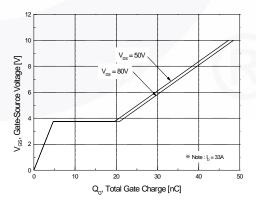


Figure 6. Gate Charge Characteristics

1.2 BA 1.1 (Namelized) 1.0 Soroe Breakdown Voltege: 1. V_{os} = 0 V 2. I_p = 250 HA

Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

 $\mathbf{T}_{_{\!J}}\!,$ Junction Temperature [°C]

150

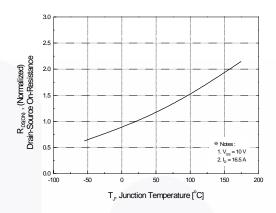


Figure 8. On-Resistance Variation vs. Temperature

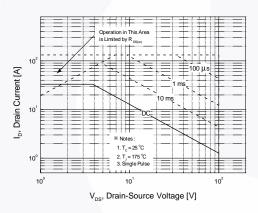


Figure 9. Maximum Safe Operating Area

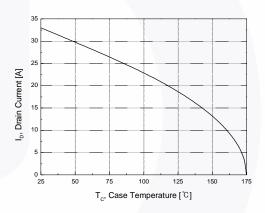


Figure 10. Maximum Drain Current vs. Case Temperature

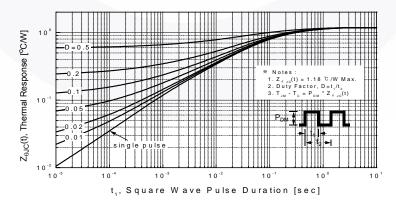


Figure 11. Transient Thermal Response Curve



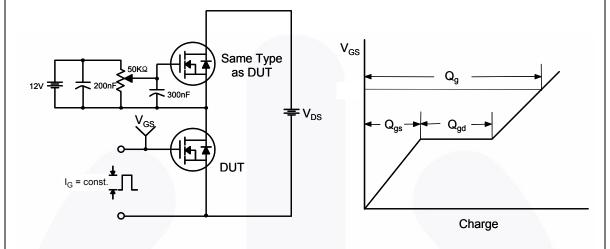


Figure 13. Resistive Switching Test Circuit & Waveforms

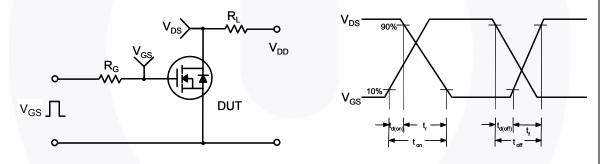
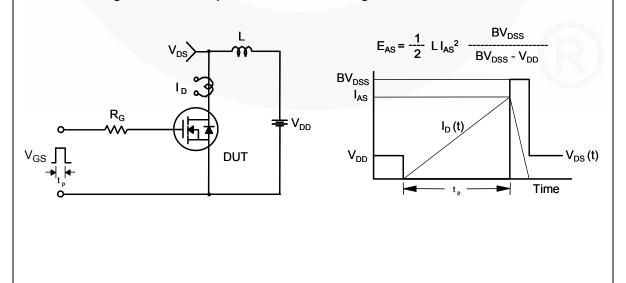
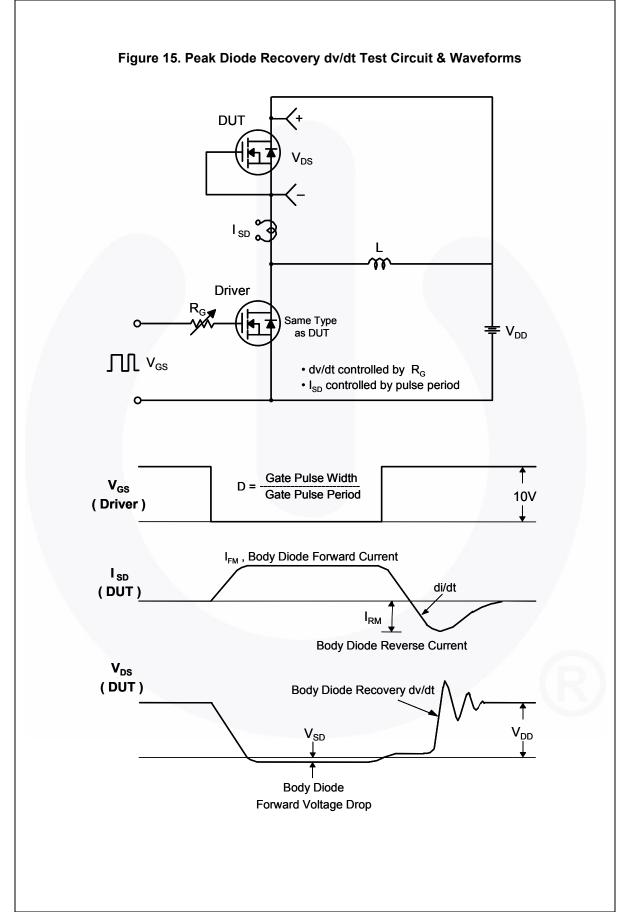


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms





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Mechanical Dimensions

TO-263 2L (D²PAK)

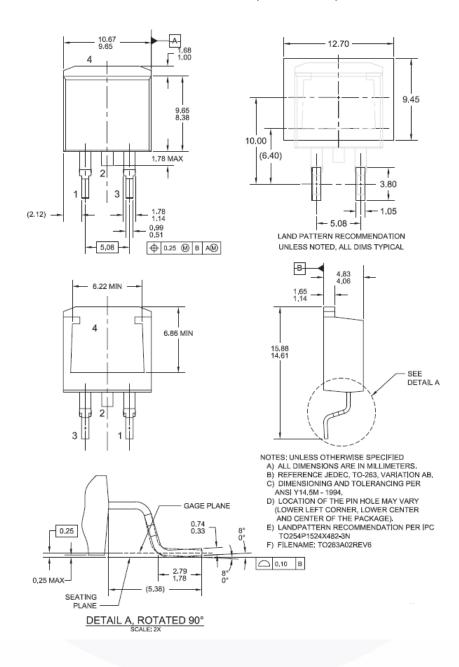


Figure 16. 2LD, TO263, Surface Mount

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Dimension in Millimeters





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